## Search Notes



Application/Control No.

Applicant(s)/Patent Under Reexamination

09687777

PATEL, MUKESH

Examiner

Nguyen-Ba, Hoang-Vu A

Art Unit 2192

Notes	Date	Examiner
East Search USPAT, US-PGPUB, EPO, JPO, DERWENT, IBM_TDB	06/21/2006	HAN
717/114-118, 139-140, 148, 165 text search only	06/21/2006	HAN
Non Patent Literature Search Google Scholar	06/21/2006	HAN
Interference Search see search history printout	06/21/2006	HAN
U.S. Patent and Trademark Office		Part of Paper No.: 20060621

## Interference Searched



Application/Control No.

Applicant(s)/Patent Under Reexamination

09687777

PATEL, MUKESH

Examiner

Nguyen-Ba, Hoang-Vu A

Art Unit

2192

Class	SubClass	Date		Examiner
717	139	06/21/2006	HAN	
717	118, 148	6/21/06	HAN	
712	41	6/21/06	HAN	

## Searched



Application/Control No.

Applicant(s)/Patent Under Reexamination

09687777

PATEL, MUKESH

Examiner

Nguyen-Ba, Hoang-Vu A

Art Unit 2192

Class	SubClass	Date	Examiner
U.S. Patent and Trademark Office	U.S. Patent and Trademark Office		art of Paper No.: 20060621